

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/699,124 SHAPIRO ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,289,450 B1	09-2001	Pensak et al.	713/167
*	B	US-2001/0056541 A1	12-2001	Matsuzaki et al.	713/193
*	C	US-6,339,825 B1	01-2002	Pensak et al.	713/158
*	D	US-2002/0046176 A1	04-2002	Seo et al.	705/51
*	E	US-2002/0095407 A1	07-2002	Itakura et al.	707/3
*	F	US-6,418,214 B1	07-2002	Smythe et al.	379/202.01
*	G	US-2002/0091640 A1	07-2002	Gupta, Dipankar	705/51
*	H	US-6,449,721 B1	09-2002	Pensak et al.	713/171
*	I	US-2003/0023657 A1	01-2003	Fischer et al.	709/102
*	J	US-2003/0055927 A1	03-2003	Fischer et al.	709/221
*	K	US-2003/0109943 A1	06-2003	Shimizu et al.	700/87
*	L	US-2003/0110131 A1	06-2003	Alain et al.	705/51
*	M	US-2003/0120601 A1	06-2003	Ouye et al.	705/51

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0105740 A1	06-2003	Shimizu et al.	707/1
*	B	US-2003/0202661 A1	10-2003	Rodriguez et al.	380/239
*	C	US-2003/0191917 A1	10-2003	McBrearty et al.	711/162
*	D	US-2003/0208686 A1	11-2003	Thummalapally et al.	713/193
*	E	US-2003/0232318 A1	12-2003	Altenhofen et al.	434/362
*	F	US-2004/0030702 A1	02-2004	Houston et al.	707/10
*	G	US-2004/0049519 A1	03-2004	Itakura et al.	707/104.1
*	H	US-2004/0049571 A1	03-2004	Johnson et al.	709/224
*	I	US-2004/0103202 A1	05-2004	Hildebrand et al.	709/229
*	J	US-2004/0117655 A1	06-2004	Someshwar, Ravi	713/201
*	K	US-2004/0146015 A1	07-2004	Cross et al.	370/328
*	L	US-2005/0044378 A1	02-2005	Beard et al.	713/182
*	M	US-6,895,289 B2	05-2005	Shimizu et al.	700/87

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,889,210 B1	05-2005	Vainstein, Klimenty	705/57
*	B	US-2005/0223414 A1	10-2005	Kenrich et al.	726/027
*	C	US-6,963,971 B1	11-2005	Bush et al.	713/153
*	D	US-6,978,376 B2	12-2005	Giroux et al.	713/189
*	E	US-2006/0002564 A1	01-2006	Aihara et al.	380/281
*	F	US-7,058,663 B2	06-2006	Johnston et al.	707/200
*	G	US-7,058,605 B2	06-2006	Gupta, Dipankar	705/51
*	H	US-7,143,419 B2	11-2006	Fischer et al.	719/328
*	I	US-7,178,033 B1	02-2007	Garcia, Denis Jacques Paul	713/184
*	J	US-7,181,016 B2	02-2007	Cross et al.	380/281
*	K	US-7,209,559 B2	04-2007	Rodriguez et al.	380/228
*	L	US-7,237,189 B2	06-2007	Altenhofen et al.	715/201
*	M	US-7,260,555 B2	08-2007	Rossmann et al.	705/51

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,367,060 B2	04-2008	Someshwar, Ravi	726/27
*	B	US-7,380,120 B1	05-2008	Garcia, Denis Jacques Paul	713/160
*	C	US-7,430,541 B2	09-2008	Seo et al.	705/51
*	D	US-7,437,614 B2	10-2008	Haswell et al.	714/38
	E	US-			
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